# **MOSFET** - Power, Single N-Channel, TOLL

40 V, 0.57 mΩ, 300 A

## **NVBLS0D5N04C**

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- Small Footprint (TOLL) for Compact Design
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parar	Symbol	Value	Unit		
Drain-to-Source Voltag	V <sub>DSS</sub>	40	V		
Gate-to-Source Voltage	9		$V_{GS}$	+20/-16	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	300	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		300	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	198.4	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		97.4	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	65	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		46	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	4.3	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		2.1	
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	4700	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			Is	170	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 55 A, L = 1 mH)			E <sub>AS</sub>	1512	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.77	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	35	

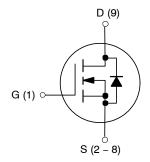
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted. Current is limited by bondwire configuration.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



## ON Semiconductor®

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
40 V	0.57 m $\Omega$ @ 10 V	300 A	



**N-CHANNEL MOSFET** 



H-PSOF8L CASE 100CU

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NVBLS0D5N04CTXG	H-PSOF8L (Pb-Free)	2000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Table 1. ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Тур	Max	Units
OFF CHARACTERISTICS	•	•					
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$I_D = 250 \mu\text{A},  V_{GS} = 0 \text{V}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				21.3		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V	T <sub>J</sub> = 25°C			1	μΑ
			T <sub>J</sub> = 175°C			1	mA
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> =	= +20/–16 V			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{GS} = V_{DS}, I_D$	= 475 μΑ	2	2.8	4	V
Threshold Temperature Coefficient	V <sub>GS(th)</sub> /T <sub>J</sub>				-7.4		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I	<sub>D</sub> = 50 A		0.5	0.57	mΩ
CHARGES, CAPACITANCES & GATE RE	SISTANCE			•			
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1 MHz			12600		pF
Output Capacitance	C <sub>oss</sub>				6705		pF
Reverse Transfer Capacitance	C <sub>rss</sub>				227		pF
Gate Resistance	Rg	V <sub>GS</sub> = 0.5 V, f = 1 MHz			1.8		Ω
Total Gate Charge	Q <sub>G(tot)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 20 V, I <sub>D</sub> = 50 A			185		nC
Threshold Gate Charge	Q <sub>G(th)</sub>	V <sub>GS</sub> = 0 to 2 V			22		nC
Gate-to-Source Gate Charge	Q <sub>gs</sub>	V <sub>DD</sub> = 32 V, I	<sub>D</sub> = 50 A		48		nC
Gate-to-Drain "Miller" Charge	Q <sub>gd</sub>				38		nC
Plateau Voltage	$V_{GP}$				4.2		V
SWITCHING CHARACTERISTICS (Note 5	)						
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{GS}$ = 10 V, $V_{DD}$ = 20 V, $I_{D}$ = 50 A, $R_{GEN}$ = 6 $\Omega$			40		ns
Turn-On Rise Time	t <sub>r</sub>	$I_D = 50 \text{ A}, H_G$	EN = 6 Ω		84		ns
Turn-Off Delay Time	t <sub>d(off)</sub>	1			164		ns
Turn-Off Fall Time	t <sub>f</sub>	1			81		ns
DRAIN-SOURCE DIODE CHARACTERIS	TICS	•			-	-	-
Source-to-Drain Diode Voltage	$V_{SD}$	I <sub>SD</sub> = 50 A, V	<sub>GS</sub> = 0 V		0.76	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS}$ = 0 V, $dI_S/d_t$ = 100 A/ $\mu$ s, $I_S$ = 50 A			108		ns
Charge Time	ta				62		ns
Discharge Time	t <sub>b</sub>				46		ns
Reverse Recovery Charge	Q <sub>rr</sub>				288		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures

#### **TYPICAL CHARACTERISTICS**

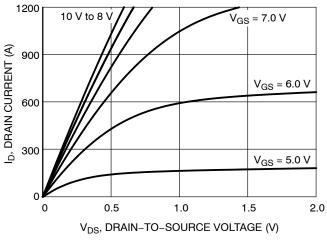
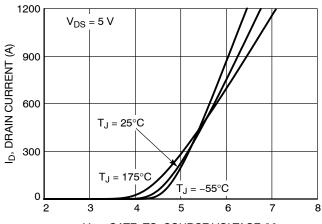


Figure 1. On-Region Characteristics



V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V) Figure 2. Transfer Characteristics

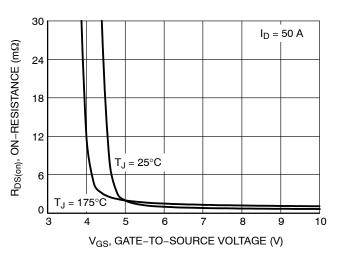


Figure 3. On-Resistance vs. Gate-to-Source Voltage

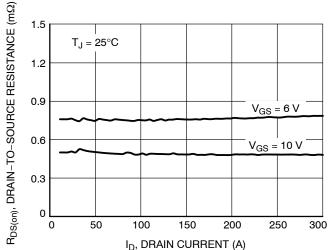


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

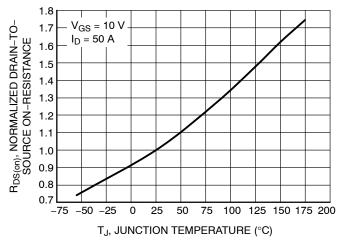


Figure 5. On–Resistance Variation with Temperature

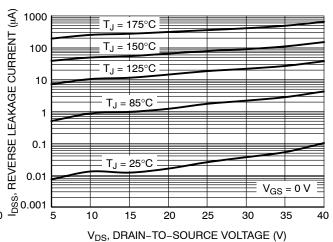


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

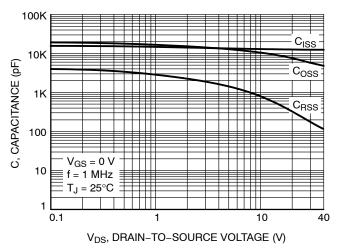


Figure 7. Capacitance Variation

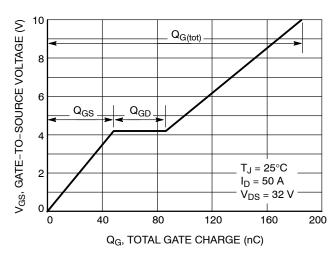


Figure 8. Gate-to-Source Voltage vs. Total Charge

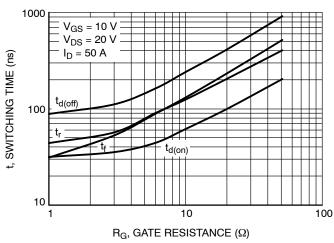


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

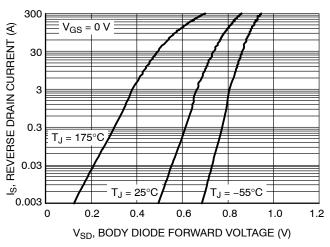


Figure 10. Diode Forward Voltage vs. Current

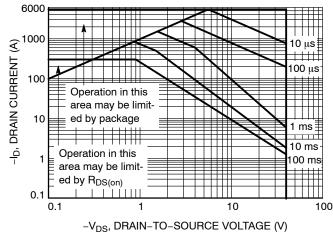


Figure 11. Forward Biased Safe Operating Area

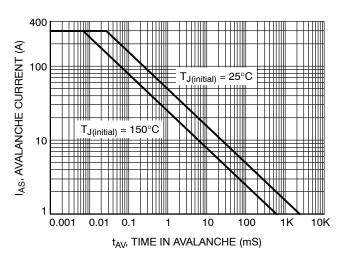


Figure 12. Maximum Drain Current vs. Time in Avalanche

## **TYPICAL CHARACTERISTICS**

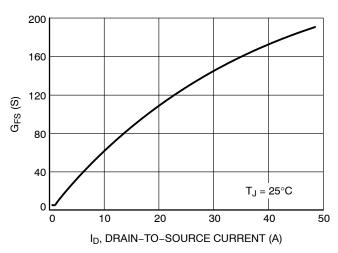


Figure 13.  $G_{FS}$  vs.  $I_D$ 

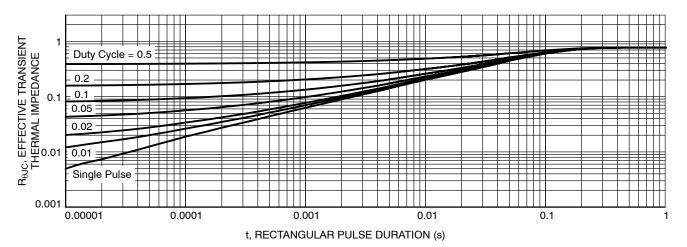


Figure 14. Transient Thermal Impedance

L

-0.10 E4 (2X)

|--D5 (3X)

D4 -

-D7

**BOTTOM VIEW** 

E5 (2X) ⊢E6 (2X)

Α

WW

ZΖ

**GENERIC MARKING DIAGRAM\*** 

AYWWZZ

XXXXXXXX XXXXXXX

= Year

= Work Week

XXXX = Specific Device Code

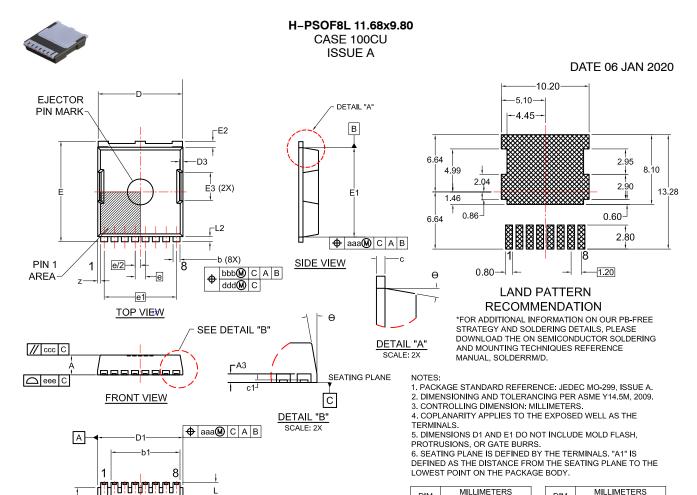
= Assembly Location

= Assembly Lot Code

E10

E9

E8 E7



	DIM	MILLIMETERS			
	Divi	MIN.	NOM.	MAX.	
	Α	2.20	2.30	2.40	
	А3	0.40	0.50	0.60	
Ī	b	0.70	0.80	0.90	
	b1		8.00 REF		
Ī	С	0.40	0.50	0.60	
	c1	0.10			
Ī	D	9.70	9.80	9.90	
Ī	D1	9.80	9.90	10.00	
[	D2	4.73 BSC			
	D3	0.40 REF			
	D4	3.75 BSC			
	D5	_	1.20		
	D6	7.40	7.50	7.60	
	D7		(8.30)		
	Е	11.58	11.68	11.78	
Ī	E1	10.28	10.38	10.48	
	E2	0.60	0.70	0.80	
	E3	3.30 REF			
	E4	_			

DIM	MILLIMETERS			
Divi	MIN.	NOM.	MAX.	
е		1.20 BSC	;	
e/2	(	0.60 BSC	,	
e1		3.40 BSC	;	
K	1.50	1.57	1.70	
L	1.90	2.00	2.10	
L2	0.50	0.60	0.70	
Z	0.35 REF			
Ө	0°		12°	
aaa	0.20			
bbb	0.25			
ccc	0.20			
ddd		0.20		
eee		0.10		
E5		3.30	_	
E6		0.65	_	
E7	7.15 REF			
E8	6.55 6.65 6.75			
E9	5.89 BSC			
F10	5 19 BSC			

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "=", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON13813G	Electronic versions are uncontrolled except when accessed directly from the Document Repositor Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	H-PSOF8L 11.68x9.80		PAGE 1 OF 1	

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

**TECHNICAL SUPPORT** North American Technical Support: Voice Mail: 1 800–282–9855 Toll Free USA/Canada

Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative